

December 1994

# 54F/74F823 9-Bit D-Type Flip-Flop

### **General Description**

The 'F823 is a 9-bit buffered register. It features Clock Enable and Clear which are ideal for parity bus interfacing in high performance microprogramming systems.

The 'F823 is functionally and pin compatible with AMD's Am29823.

#### **Features**

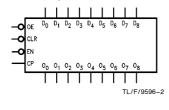
- TRI-STATE® outputs
- Clock Enable and Clear
- Direct replacement for AMD's Am29823

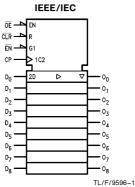
Commercial	Military	Package Number	Package Description			
74F823SPC		N24C	24-Lead (0.300" Wide) Molded Dual-In-Line			
	54F823SDM (Note 2)	J24F	24-Lead (0.300" Wide) Ceramic Dual-In-Line			
74F823SC (Note 1)		M24B	24-Lead (0.300" Wide) Molded Small Outline, JEDEC			
	54F823FM (Note 2)	W24C	24-Lead Cerpack			
	54F823LM (Note 2)	E28A	24-Lead Ceramic Chip Carrier, Type C			

Note 1: Devices also available in 13" reel. Use suffix = SCX.

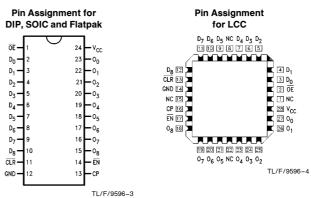
Note 2: Military grade device with environmental and burn-in processing. Use suffix = SDMQB, FMQB and LMQB.

#### **Logic Symbols**





#### **Connection Diagrams**



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RRD-B30M75/Printed in U. S. A.

# Unit Loading/Fan Out

		54F/74F					
Pin Names	Description	U.L. HIGH/LOW	Input I <sub>IH</sub> /I <sub>IL</sub> Output I <sub>OH</sub> /I <sub>OL</sub>				
D <sub>0</sub> -D <sub>8</sub>	Data Inputs	1.0/1.0	20 μA/-0.6 mA				
ŌĒ	Output Enable Input	1.0/1.0	20 μA/-0.6 mA				
CLR	Clear	1.0/1.0	20 μA/ – 0.6 mA				
CP	Clock Input	1.0/2.0	20 μA/ – 1.2 mA				
EN	Clock Enable	1.0/1.0	20 μA/ – 0.6 mA				
$O_0 - O_8$	TRI-STATE Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)				

## **Functional Description**

The 'F823 device consists of nine D-type edge-triggered The Po2s device consists of fine D-type edge-triggered flip-flops. It has TRI-STATE true outputs and is organized in broadside pinning. The buffered Clock (CP) and buffered Output Enable  $(\overline{\text{OE}})$  are common to all flip-flops. The flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the LOW-to-HIGH CP transition. With the  $\overline{\text{OE}}$  LOW the contents of the flipflops are available at the outputs. When the  $\overline{\text{OE}}$  is HIGH, the outputs go to the high impedance state. Operation of the OE input does not affect the state of the flip-flops. In addi-

tion to the Clock and Output Enable pins, the 'F823 has Clear (CLR) and Clock Enable (EN) pins.

When the  $\overline{\text{CLR}}$  is LOW and the  $\overline{\text{OE}}$  is LOW, the outputs are LOW. When CLR is HIGH, data can be entered into the flipflops. When  $\overline{\text{EN}}$  is LOW, data on the inputs is transferred to the outputs on the LOW to HIGH clock transition. When the  $\overline{\text{EN}}$  is HIGH, the outputs do not change state regardless of the data or clock inputs transitions. This device is ideal for parity bus interfacing in high performance systems.

#### **Function Table**

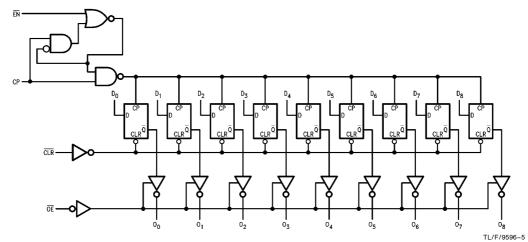
	Inputs			Inputs Internal Output				
ŌĒ	CLR	ĒΝ	СР	D	Q	0	Function	
Н	Н	L	Н	Χ	NC	Z	Hold	
Н	Н	L	L	Χ	NC	Z	Hold	
Н	Н	Н	Χ	Χ	NC	Z	Hold	
L	Н	Н	Χ	Χ	NC	NC	Hold	
Н	L	X	X	Χ	Н	Z	Clear	
L	L	X	Χ	Χ	Н	L	Clear	
Н	Н	L	$\mathcal{L}$	Н	Н	Z	Load	
Н	Н	L	$\mathcal{L}$	Н	L	Z	Load	
L	Н	L	$\mathcal{L}$	L	Н	L	Data Available	
L	Н	L	$\mathcal{L}$	Н	L	Н	Data Available	
L	Н	L	Н	Χ	NC	NC	No Change in Data	
L	Н	L	L	Χ	NC	NC	No Change in Data	

- L = LOW Voltage Level
- H = HIGH Voltage Level
  X = Immaterial
- Z = High Impedance

  Z = LOW-to-HIGH Transition

  NC = No Change

# **Logic Diagram**



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C -55°C to +175°C Junction Temperature under Bias Plastic  $-55^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$ 

V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0V

Input Current (Note 2)  $-30\ \text{mA}$  to  $+5.0\ \text{mA}$ 

Voltage Applied to Output in HIGH State (with V<sub>CC</sub> = 0V)

 $-0.5 \mbox{V to V}_{CC} \\ -0.5 \mbox{V to } +5.5 \mbox{V}$ Standard Output TRI-STATE Output

Current Applied to Output

twice the rated  $I_{OL}$  (mA) in LOW State (Max)

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

## **Recommended Operating Conditions**

Free Air Ambient Temperature

 $-55^{\circ}\text{C to} + 125^{\circ}\text{C}$ Military Commercial  $0^{\circ}\text{C}$  to  $+\,70^{\circ}\text{C}$ 

Supply Voltage

+4.5V to +5.5VMilitary Commercial  $\pm$  4.5V to  $\pm$  5.5V

#### **DC Electrical Characteristics**

Symbol	Parameter		54F/74F			Units	V <sub>CC</sub>	Conditions		
Syllibol	Faranie	tei	Min	Тур	Max	Oilles	VCC	Conditions		
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal		
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal		
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	$I_{\text{IN}} = -18 \text{ mA}$		
V <sub>OH</sub>	Output HIGH Voltage	54F 10% V <sub>CC</sub> 54F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub> 74F 5% V <sub>CC</sub> 74F 5% V <sub>CC</sub>	2.5 2.4 2.5 2.4 2.7 2.7			٧	Min	$\begin{split} I_{OH} &= -1 \text{ mA} \\ I_{OH} &= -3 \text{ mA} \\ I_{OH} &= -1 \text{ mA} \\ I_{OH} &= -3 \text{ mA} \\ I_{OH} &= -1 \text{ mA} \\ I_{OH} &= -3 \text{ mA} \\ \end{split}$		
V <sub>OL</sub>	Output LOW Voltage	54F 10% V <sub>CC</sub> 74F 10% V <sub>CC</sub>			0.5 0.5	V	Min	I <sub>OL</sub> = 20 mA I <sub>OL</sub> = 24 mA		
I <sub>IH</sub>	Input HIGH Current	54F 74F			20.0 5.0	μΑ	Max	V <sub>IN</sub> = 2.7V		
I <sub>BVI</sub>	Input HIGH Current Breakdown Test	54F 74F			100 7.0	μΑ	Max	V <sub>IN</sub> = 7.0V		
I <sub>CEX</sub>	Output HIGH Leakage Current	54F 74F			250 50	μΑ	Max	$V_{OUT} = V_{CC}$		
V <sub>ID</sub>	Input Leakage Test	74F	4.75			V	0.0	$I_{\text{ID}} = 1.9  \mu\text{A}$ All Other Pins Grounded		
I <sub>OD</sub>	Output Leakage Circuit Current	74F			3.75	μΑ	0.0	V <sub>IOD</sub> = 150 mV All Other Pins Grounded		
I <sub>IL</sub>	Input LOW Current				−0.6 −1.2	mA mA	Max Max	$V_{IN} = 0.5V (\overline{OE}, \overline{CLR}, \overline{EN})$ $V_{IN} = 0.5V (CP)$		
lozh	Output Leakage Current				50	μΑ	Max	V <sub>OUT</sub> = 2.7V		
l <sub>OZL</sub>	Output Leakage Current				-50	μΑ	Max	V <sub>OUT</sub> = 0.5V		
los	Output Short-Circuit Current		-60		-150	mA	Max	V <sub>OUT</sub> = 0V		
I <sub>ZZ</sub>	Buss Drainage Test				500	μΑ	0.0V	V <sub>OUT</sub> = 5.25V		
I <sub>CCZ</sub>	Power Supply Curren	t		75	100	mA	Max	V <sub>O</sub> = HIGH Z		

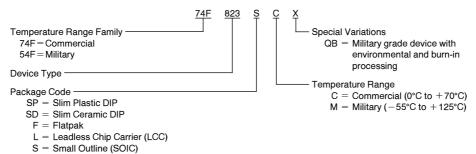
AC EI	ectrical Characteri	stics							
		74F			54F		74F		
Symbol	Parameter	v	T <sub>A</sub> = +25° / <sub>CC</sub> = +5.0 C <sub>L</sub> = 50 pl	v	T <sub>A</sub> , V <sub>CC</sub> = Mil C <sub>L</sub> = 50 pF		T <sub>A</sub> , V <sub>CC</sub> = Com C <sub>L</sub> = 50 pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
f <sub>max</sub>	Maximum Clock Frequency	100	160		60		70		MHz
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay CP to O <sub>n</sub>	2.0 2.0	5.6 5.2	9.5 9.5	2.0 2.0	10.5 10.5	2.0 2.0	10.5 10.5	ns
t <sub>PHL</sub>	Propagation Delay CLR to On	4.0	7.1	12.0	4.0	13.0	4.0	13.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable Time OE to On	2.0 2.0	5.8 5.5	10.5 10.5	2.0 2.0	13.0 13.0	2.0 2.0	11.5 11.5	- ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable Time OE to O <sub>n</sub>	1.5 1.5	2.9 2.7	7.0 7.0	1.0 1.0	7.5 7.5	1.5 1.5	7.5 7.5	113

# **AC Operating Requirements**

				54	F	74F  T <sub>A</sub> , V <sub>CC</sub> = Com		Units
Symbol	Parameter			T <sub>A</sub> , V <sub>CC</sub>	; = Mil			
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H) t <sub>S</sub> (L)	Setup Time, HIGH or LOW D <sub>n</sub> to CP	2.5 2.5		4.0 4.0		3.0 3.0		ns
t <sub>h</sub> (H)	Hold Time, HIGH or LOW D <sub>n</sub> to CP	2.5 2.5		2.5 2.5		2.5 2.5		113
t <sub>s</sub> (H)	Setup Time, HIGH or LOW EN to CP	4.5 2.5		5.0 3.0		5.0 3.0		- ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold Time, HIGH or LOW EN to CP	2.0 0		3.0 1.0		2.0 0		113
t <sub>w</sub> (H)	CP Pulse Width HIGH or LOW	5.0 5.0		6.0 6.0		6.0 6.0		ns
t <sub>w</sub> (L)	CLR Pulse Width, LOW	5.0		5.0		5.0		ns
t <sub>rec</sub>	CLR Recovery Time	5.0		5.0		5.0		ns

### **Ordering Information**

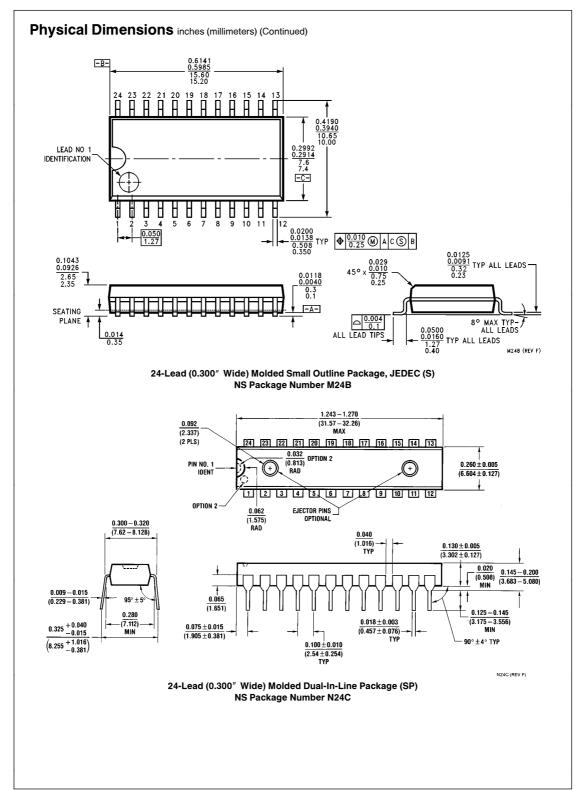
The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:



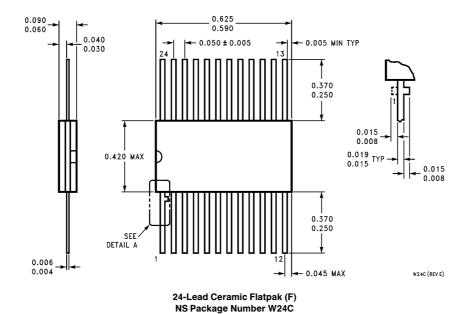
#### Physical Dimensions inches (millimeters) 0.015 MIN TYP -PIN #1 INDEX 0.300 ± 0.005 TYP \_ 0.075 0.063 -□0.450 ± 0.008 0.011 0.007 TYP 0.093 0.077 -0.003 MIN TYP <u></u> 0.015 MAX 0.028 0.022 TYP 0.022 MAX TYP 0.055 0.045 1-19 0.055 0.045 TYP 18 ·45° x 0.040±0.010 DETAIL A 0.083 0.067 TYP BOTTOM VIEW SIDE VIEW TOP VIEW E28A (REV D) 28-Lead Ceramic Leadless Chip Carrier, Type C (L) NS Package Number E28A 0.025 (0.635) RAD - (32.77) MAX 24 23 22 21 20 19 18 17 16 15 14 13

0.315 MAX (8.001) GLASS (7.493) MAX 1 2 3 4 5 6 7 8 9 10 11 12 0.030-0.055 (0.762-1.397) RAD TYP  $\frac{0.060~\pm0.005}{(1.524~\pm0.127)}~\rm TYP$ GLASS SEALANT 0.290-0.320 0.020-0.070 (7.366-8.128) (0.508-1.778) 0.180 0.225 (4.572) (5.715) MAX 0.008-0.012 (0.203-0.305) TYP 0.095 MAX (2.413) BOTH ENDS 0.125 0.310-0.410 (3.175) (7.874-10.41)

24-Lead (0.300" Wide) Ceramic Dual-In-Line Package (SD) NS Package Number J24F



### Physical Dimensions inches (millimeters) (Continued)



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